Because of an order from the United States International Trade Commission, BGA-packaged product lines and part numbers indicated here currently are not available rom Freescale for import or sale in the United States prior to September 2010: MCF523x products in 196 MAPBGA and 256 MAPBGA packages

Freescale Semiconductor

Data Sheet: Technical Data

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MCF523x Integrated Microprocessor Hardware Specification

by: Microcontroller Solutions Group

The MCF523x is a family of highly-integrated 32-bit microcontrollers based on the V2 ColdFire microarchitecture. Featuring a 16 or 32 channel eTPU, 64 Kbytes of internal SRAM, a 2-bank SDRAM controller, four 32-bit timers with dedicated DMA, a 4 channel DMA controller, up to 2 CAN modules, 3 UARTs and a queued SPI, the MCF523x family has been designed for general purpose industrial control applications. It is also a high-performance upgrade for users of the MC68332. This document provides an overview of the MCF523x microcontroller family, as well as detailed descriptions of the mechanical and electrical characteristics of the devices.

The MCF523*x* family is based on the Version 2 ColdFire reduced instruction set computing (RISC) microarchitecture operating at a core frequency of up to 150 MHz and bus frequency up to 75 MHz.

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1 MCF523x Family Configurations

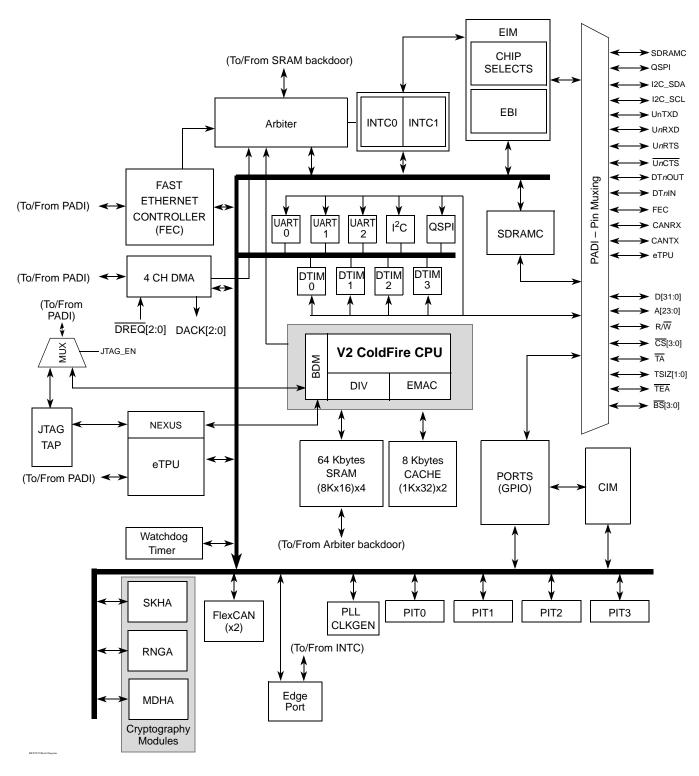
Table 1. MCF523x Family Configurations

Module	MCF5232	MCF5233	MCF5234	MCF5235
ColdFire V2 Core with EMAC (Enhanced Multiply-Accumulate Unit)	Х	х	х	Х
Enhanced Time Processor Unit with memory (eTPU)	16-ch 6K	32-ch 6K	16-ch 6K	32-ch 6K
System Clock		up to 1	50 MHz	
Performance (Dhrystone/2.1 MIPS)		up to	144	
Instruction/Data Cache		8 Kb	ytes	
Static RAM (SRAM)		64 K	bytes	
Interrupt Controllers (INTC)	2	2	2	2
Edge Port Module (EPORT)	х	х	х	х
External Interface Module (EIM)	х	х	х	х
4-channel Direct-Memory Access (DMA)	х	х	х	х
SDRAM Controller	х	х	х	х
Fast Ethernet Controller (FEC)	_	_	х	х
Cryptography - Security module for data packets processing	_	_	_	х
Watchdog Timer (WDT)	х	х	х	х
Four Periodic Interrupt Timers (PIT)	х	х	х	х
32-bit DMA Timers	4	4	4	4
QSPI	х	х	х	х
UART(s)	3	3	3	3
I ² C	х	х	х	х
FlexCAN 2.0B - Controller-Area Network communication module	1	2	1	2
General Purpose I/O Module (GPIO)	х	х	х	х
JTAG - IEEE 1149.1 Test Access Port	х	х	х	х
Package	160 QFP 196 MAPBGA	256 MAPBGA	256 MAPBGA	256 MAPBGA

2 Block Diagram

The superset device in the MCF523x family comes in a 256 mold array process ball grid array (MAPBGA) package. Figure shows a top-level block diagram of the MCF5235, the superset device.

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3 Features

For a detailed feature list see the MCF5235 Reference Manual (MCF5235RM).

Signal Descriptions

4 Signal Descriptions

This section describes signals that connect off chip, including a table of signal properties. For a more detailed discussion of the MCF523*x* signals, consult the *MCF5235 Reference Manual* (MCF5235RM).

4.1 Signal Properties

Table 2 lists all of the signals grouped by function. The "Dir" column is the direction for the primary function of the pin. Refer to Section 6, "Mechanicals/Pinouts and Part Numbers," for package diagrams.

NOTE

In this table and throughout this document a single signal within a group is designated without square brackets (i.e., A24), while designations for multiple signals within a group use brackets (i.e., A[23:21]) and is meant to include all signals within the two bracketed numbers when these numbers are separated by a colon.

NOTE

The primary functionality of a pin is not necessarily its default functionality. Pins that are muxed with GPIO will default to their GPIO functionality.

Table 2. MCF523x Signal Information and Muxing

Signal Name	GPIO	Alternate 1	Alternate 2	Dir. ¹	MCF5232 160 QFP	MCF5232 196 MAPBGA	MCF5233 256 MAPBGA	MCF5234 256 MAPBGA	MCF5235 256 MAPBGA		
Reset											
RESET	_	_	_	I	83	N13	T15	T15	T15		
RSTOUT		_	_	0	82	P13	T14	T14	T14		
Clock											
EXTAL	_	_	_	I	86	M14	P16	P16	P16		
XTAL	_	_	_	0	85	N14	R16	R16	R16		
CLKOUT	_	_	_	0	89	K14	M16	M16	M16		
			N	/lode S	Selection						
CLKMOD[1:0]	_	_	_	I	19,20	G5, H5	J3, J2	J3, J2	J3, J2		
RCON	_	_	_	I	79	K10	P13	P13	P13		
	External Memory Interface and Ports										
A[23:21]	PADDR[7:5]	CS[6:4]	_	0	126, 125, 124	B11, C11, D11	B14, C14, A15	B14, C14, A15	B14, C14, A15		

Table 2. MCF523x Signal Information and Muxing (continued)

					MCF5232	MCF5232	MCF5233	MCF5234	MCF5235
Signal Name	GPIO	Alternate 1	Alternate 2	Dir. ¹	160 QFP	196 MAPBGA	256 MAPBGA	256 MAPBGA	256 MAPBGA
A[20:0]		_	_	0	123:115, 112:106, 102:98	A12, B12, C12, A13, B13, B14, C13, C14, D12, D13, D14, E11, E12, E13, E14, F12, F13, F14, G11, G12, G13	B15, B16, C15, C16, D16, D15, D14, E16, E15, E14, E13, F15, F14, F13, G15, G14, G13, H16, H15, H14, H13	B15, B16, C15, C16, D16, D15, D14, E16, E15, E14, E13, F15, F14, F13, G15, G14, G13, H16, H15, H14, H13	B15, B16, C15, C16, D16, D15, D14, E16, E15, E14, E13, F15, F14, F13, G15, G14, G13, H16, H15, H14, H13
D[31:16]	I	_	_	0	21:24, 26:30, 33:39	G1, G2, H1, H2, H3, H4, J1, J2, J3, J4, K1, K2, K3, K4, L1, L2	K4, K3, K2, K1, L4, L3, L2, L1, M3, M2, M1, N2, N1, P2, P1, R1	K4, K3, K2, K1, L4, L3, L2, L1, M3, M2, M1, N2, N1, P2, P1, R1	L2, L1, M3, M2, M1,
D[15:8]	PDATAH[7:0]	_	_	0	42:49,	M1, N1, M2, N2, P2, L3, M3, N3,	R2, T2, N3, P3, R3, T3, N4, P4,	R2, T2, N3, P3, R3, T3, N4, P4,	R2, T2, N3, P3, R3, T3, N4, P4,
D[7:0]	PDATAL[7:0]	_	_	0	50:52, 56:60	P3, M4, N4, P4, L5, M5, N5, P5	R4, T4, P5, R5, N6, P6, R6, N7	R4, T4, P5, R5, N6, P6, R6, N7	R4, T4, P5, R5, N6, P6, R6, N7
BS[3:0]	PBS[7:4]	CAS[3:0]	_	0	143:140	B6, C6, D7, C7	C9, B9, A9, A10	C9, B9, A9, A10	C9, B9, A9, A10
ŌĒ	PBUSCTL7	_	_	0	63	N6	T7	T7	T7
TA	PBUSCTL6	_	_	I	97	H11	K14	K14	K14
TEA	PBUSCTL5	DREQ1	_	I	_	J14	K13	K13	K13
R/W	PBUSCTL4	_	_	0	96	J13	L16	L16	L16
TSIZ1	PBUSCTL3	DACK1	_	0	_	P6	N8	N8	N8
TSIZ0	PBUSCTL2	DACK0	_	0	_	P7	P8	P8	P8
TS	PBUSCTL1	DACK2	_	0	_	H13	K16	K16	K16
TIP	PBUSCTL0	DREQ0	_	0	_	H12	K15	K15	K15
				Chip	Selects				
CS[7:4]	PCS[7:4]	_	_	0	_	B9, A10, C10, A11	C12, A13, C13, A14	C12, A13, C13, A14	C12, A13, C13, A14
CS[3:2]	PCS[3:2]	SD_CS[1:0]	_	0	134,133	A9, C9	B12, D12	B12, D12	B12, D12
CS1	PCS1	_	_	0	130	B10	B13	B13	B13
CS0	_	_	_	0	129	D10	D13	D13	D13
			SE	RAM	Controller				

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Signal Descriptions

Table 2. MCF523x Signal Information and Muxing (continued)

Signal Name	GPIO	Alternate 1	Alternate 2	Dir. ¹	MCF5232 160 QFP	MCF5232 196 MAPBGA	MCF5233 256 MAPBGA	MCF5234 256 MAPBGA	MCF5235 256 MAPBGA		
SD_WE	PSDRAM5	_	_	0	93	K13	L13	L13	L13		
SD_SCAS	PSDRAM4	_	_	0	92	K12	M15	M15	M15		
SD_SRAS	PSDRAM3	_	_	0	91	K11	M14	M14	M14		
SD_CKE	PSDRAM2	_	_	0	_	E8	C10	C10	C10		
SD_CS[1:0]	PSDRAM[1:0]	_	_	0	_	L12, L13	N15, M13	N15, M13	N15, M13		
			Exte	rnal In	terrupts Port	•	•	1	•		
IRQ7=64 N7, M7, L7, R8, T8, N9, N8, N8, N8, N8, N8, N8, N8, N8, N8, N8											
ĪRQ2	PIRQ2	DREQ2	_	I	_	M8	Т9	T9	Т9		
ĪRQ1	PIRQ1	_	_	I	66	L8	N10	N10	N10		
				e ⁻	ТРИ	•	•	1			
TPUCH31	_	ECOL	_		_	_	F3	_	F3		
TPUCH30	_	ECRS	_		_	_	F4	_	F4		
TPUCH29	_	ERXCLK	_		_	_	E3	_	E3		
TPUCH28	_	ERXDV	_		_	_	E4	_	E4		
TPUCH[27:24]	_	ERXD[3:0]	_		_	_	D3, D4, C3, C4	_	D3, D4, C3, C4		
TPUCH23	_	ERXER	_		_	_	D5	_	D5		
TPUCH22	2 — ETXCLK		_		_	_	C5	_	C5		
TPUCH21	_	ETXEN	_		_	_	D6	_	D6		
TPUCH20	_	ETXER	_		_	_	C6	_	C6		
TPUCH[19:16]	_	ETXD[3:0]	_		_	_	B6,B5, A5, B7	_	B6,B5, A5, B7		
TPUCH[15:0]	_	-	_		11, 10, 7:2, 159:154, 152, 151	D2, D3, C1, C2, B1, B2, A2, C3, B3,	D1, D2, C1, C2, B1, B2, A2, B3, A3,	F2, E1, E2, D1, D2, C1, C2, B1, B2, A2, B3, A3, B4, A4, A6, A7	D1, D2, C1, C2, B1, B2, A2, B3, A3,		
TCRCLK	PETPU2	_	_		12	E3	F1	F1	F1		
UTPUODIS	PETPU1	_	_		_	H10	J13	J13	J13		
LTPUODIS	PETPU0		_			G10	J14	J14	J14		
				F	EC						
EMDIO	PFECI2C2	I2C_SDA	U2RXD	I/O	_	_	_	C7	C7		
EMDC	PFECI2C3	I2C_SCL	U2TXD	0	_	_	_	D7	D7		
ECOL	_	_	_	I	_	_	_	F3	F3		

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Table 2. MCF523x Signal Information and Muxing (continued)

			_						
Signal Name	GPIO	Alternate 1	Alternate 2	Dir. ¹	MCF5232 160 QFP	MCF5232 196 MAPBGA	MCF5233 256 MAPBGA	MCF5234 256 MAPBGA	MCF5235 256 MAPBGA
ECRS	_	_	_	I	_	_	_	F4	F4
ERXCLK	_	_	_	I	_	_	_	E3	E3
ERXDV	_	_	_	I	_	_	_	E4	E4
ERXD[3:0]	_	_	_	I	_	_	_	D3, D4, C3, C4	D3, D4, C3, C4
ERXER	_	_	_	I	_	_	_	D5	D5
ETXCLK	_	_	_	I	_	_	_	C5	C5
ETXEN	_	_	_	0	_	_	_	D6	D6
ETXER	_	_	_	0	_	_	_	C6	C6
ETXD[3:0]	_	_	_	0	_	_	_	B6, B5, A5, B7	B6, B5, A5, B7
			F	eatur	e Control				
eTPU/EthENB	_	_	_	I	_	_	_	_	M4
				ı	² C				
I2C_SDA	PFECI2C1	CAN0RX	_	I/O	_	J12	L15	L15	L15
I2C_SCL	PFECI2C0	CAN0TX	_	I/O	_	J11	L14	L14	L14
-		1	•	D	MA	1	•	1	•
DACK[2:0] and I Please TS and DT2OL TSIZ0 and DT0 TEA and DT1II	refer to the fo JT for DACK2, OUT for DACK	llowing pins fo TSIZ1and DT .0, IRQ2 and I	or muxing: 10UT for DA DT2IN for DR	CK1, EQ2,	_	_	_	_	_
				Q	SPI				
QSPI_CS1	PQSPI4	SD_CKE	_	0	139	B7	B10	B10	B10
QSPI_CS0	PQSPI3	_	_	0	147	A6	D9	D9	D9
QSPI_CLK	PQSPI2	I2C_SCL	_	0	148	C5	B8	B8	B8
QSPI_DIN	PQSPI1	I2C_SDA	_	I	149	B5	C8	C8	C8
QSPI_DOUT	PQSPI0	_	_	0	150	A5	D8	D8	D8
				U/	ARTs				
U2TXD	PUARTH1	CAN1TX	_	0	_	A8	D11	D11	D11
U2RXD	PUARTH0	CAN1RX	_	I	_	A7	D10	D10	D10
U1CTS	PUARTL7	U2CTS	_	I	_	B8	C11	C11	C11
U1RTS	PUARTL6	U2RTS	_	0	_	C8	B11	B11	B11
U1TXD	PUARTL5	CAN0TX	_	0	135	D9	A12	A12	A12

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Signal Descriptions

Table 2. MCF523x Signal Information and Muxing (continued)

Signal Name	GPIO	Alternate 1	Alternate 2	Dir. ¹	MCF5232 160 QFP	MCF5232 196 MAPBGA	MCF5233 256 MAPBGA	MCF5234 256 MAPBGA	MCF5235 256 MAPBGA			
U1RXD	PUARTL4	CAN0RX	CANORX —		136	D8	A11	A11	A11			
U0CTS	PUARTL3	_	_	I	_	F3	G1	G1	G1			
U0RTS	PUARTL2	_	_	0	_	G3	H3	НЗ	НЗ			
U0TXD	PUARTL1	_	_	0	14	F1	H2	H2	H2			
U0RXD	PUARTL0	_	_	I	13	F2	G2	G2	G2			
DMA Timers												
DT3IN	PTIMER7	U2CTS	QSPI_CS2	I	_	H14	J15	J15	J15			
DT3OUT	PTIMER6	U2RTS	QSPI_CS3	0	_	G14	J16	J16	J16			
DT2IN	PTIMER5	DREQ2	DT2OUT	I	_	M9	P10	P10	P10			
DT2OUT	PTIMER4	DACK2	_	0	_	L9	R10	R10	R10			
DT1IN	PTIMER3	DREQ1	DT1OUT	I	_	L6	P7	P7	P7			
DT1OUT	PTIMER2	DACK1	_	0	_	M6	R7	R7	R7			
DT0IN	PTIMER1	DREQ0	_	I	_	E4	G4	G4	G4			
DT0OUT	PTIMER0	DACK0	_	0	_	F4	G3	G3	G3			
				BDM	/JTAG ²							
DSCLK	_	TRST	_	I	70	N9	N11	N11	N11			
PSTCLK	_	TCLK	_	0	68	P9	T10	T10	T10			
BKPT	_	TMS	_	I	71	P10	P11	P11	P11			
DSI	_	TDI	_	I	73	M10	T11	T11	T11			
DSO	_	TDO	_	0	72	N10	R11	R11	R11			
JTAG_EN	_	_	_	I	78	K9	N13	N13	N13			
DDATA[3:0]		_	_	0	-	M12, N12, P12, L11	N14, P14, T13, R13	N14, P14, T13, R13	N14, P14, T13, R13			
PST[3:0]	_	_	_	0	77:74	M11, N11, P11, L10	T12, R12, P12, N12	T12, R12, P12, N12	T12, R12, P12, N12			

MCF5232 MCF5232 MCF5233 MCF5234 MCF5235 Alternate 1 | Alternate 2 | Dir. 1 **GPIO** Signal Name 160 196 256 256 256 **MAPBGA MAPBGA QFP MAPBGA MAPBGA Test TEST** 18 F5 J4 J4 J4 R14 R14 PLL_TEST R14 **Power Supplies VDDPLL** P15 87 M13 VSSPLL ı 84 L14 R15 1, 9, 17, 32, E6:11, F5, F7:10, F12, G5, G6, G11, **OVDD** E5, E7, E10, F7, F9, 41, 55, 62, G12, H5, H6, H11, H12, J5, J6, J11, 69.81.90. G6, G8, H7, J12, K5, K6, K11, K12, L5, L7:10, 95, 105, 114, H8, H9, J6, L12, M6:M11 128, 132, J8, J10, K5, 138, 146 K6, K8 8, 16, 25, 31, **VSS** A1, A14, A1, A16, E5, E12, F6, F11, F16, E6, E9, F6, 40, 54, 61, G7:10, H7: 10, J1, J7:10, K7:10, L6, F8, F10, L11, M5, M12, N16, T1, T6, T16 67, 80, 88, G7, G9, H6, 94, 104, 113, J5, J7, J9, 127, 131, 137, 145, K7, P1, P14 153, 160 **VDD** I 15, 53, 103, D6, F11, A8, G16, H1, T5 144 G4, L4

Table 2. MCF523x Signal Information and Muxing (continued)

5 Design Recommendations

5.1 Layout

- Use a 4-layer printed circuit board with the VDD and GND pins connected directly to the power and ground planes for the MCF523x.
- See application note AN1259, System Design and Layout Techniques for Noise Reduction in Processor-Based Systems.
- Match the PC layout trace width and routing to match trace length to operating frequency and board impedance. Add termination (series or therein) to the traces to dampen reflections. Increase the PCB impedance (if possible) keeping the trace lengths balanced and short. Then do cross-talk analysis to separate traces with significant parallelism or are otherwise "noisy". Use 6 mils trace and separation. Clocks get extra separation and more precise balancing.

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Refers to pin's primary function. All pins which are configurable for GPIO have a pullup enabled in GPIO mode with the exception of PBUSCTL[7], PBUSCTL[4:0], PADDR, PBS, PSDRAM.

² If JTAG_EN is asserted, these pins default to Alternate 1 (JTAG) functionality. The GPIO module is not responsible for assigning these pins.

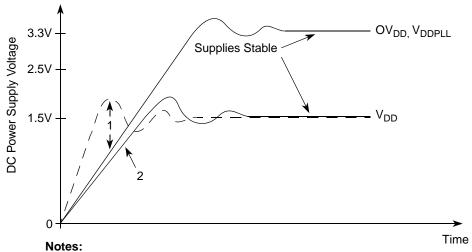
Design Recommendations

5.2 Power Supply

• 33 μF, 0.1 μF, and 0.01 μF across each power supply

5.2.1 Supply Voltage Sequencing and Separation Cautions

Figure 1 shows situations in sequencing the I/O V_{DD} (OV_{DD}), PLL V_{DD} (V_{DDPLL}), and Core V_{DD} (V_{DD}). OV_{DD} is specified relative to V_{DD} .



- VDD should not exceed OVDD or VDDPLL by more than 0.4 V at any time, including power-up.
- Recommended that VDD should track OVDD/VDDPLL up to 0.9 V, then separate for completion of ramps.
- 3. Input voltage must not be greater than the supply voltage (OVDD, VDD, or VDDPLL) by more than 0.5 V at any time, including during power-up.
- 4. Use 1 ms or slower rise time for all supplies.

Figure 1. Supply Voltage Sequencing and Separation Cautions

5.2.1.1 Power Up Sequence

If OV_{DD} is powered up with V_{DD} at 0 V, then the sense circuits in the I/O pads cause all pad output drivers connected to the OV_{DD} to be in a high impedance state. There is no limit on how long after OV_{DD} powers up before V_{DD} must power up. V_{DD} should not lead the OV_{DD} or V_{DDPLL} by more than 0.4 V during power ramp-up, or there will be high current in the internal ESD protection diodes. The rise times on the power supplies should be slower than 1 µs to avoid turning on the internal ESD protection clamp diodes.

The recommended power up sequence is as follows:

- 1. Use 1 ms or slower rise time for all supplies.
- 2. V_{DD} and OV_{DD}/V_{DDPLL} should track up to 0.9 V, then separate for the completion of ramps with OV_{DD} going to the higher external voltages. One way to accomplish this is to use a low drop-out voltage regulator.

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5.2.1.2 Power Down Sequence

If V_{DD} is powered down first, then sense circuits in the I/O pads cause all output drivers to be in a high impedance state. There is no limit on how long after V_{DD} powers down before OV_{DD}/V_{DDPLL} must power down. V_{DD} should not lag OV_{DD} or V_{DDPLL} going low by more than 0.4 V during power down or there will be undesired high current in the ESD protection diodes. There are no requirements for the fall times of the power supplies.

The recommended power down sequence is as follows:

- 1. Drop V_{DD} to 0 V.
- 2. Drop OV_{DD}/V_{DDPLL} supplies.

5.3 Decoupling

- Place the decoupling caps as close to the pins as possible, but they can be outside the footprint of the package.
- 0.1 μF and 0.01 μF at each supply input

5.4 Buffering

• Use bus buffers on all data/address lines for all off-board accesses and for all on-board accesses when excessive loading is expected. See Section 7, "Electrical Characteristics."

5.5 Pull-up Recommendations

• Use external pull-up resistors on unused inputs. See pin table.

5.6 Clocking Recommendations

- Use a multi-layer board with a separate ground plane.
- Place the crystal and all other associated components as close to the EXTAL and XTAL (oscillator pins) as possible.
- Do not run a high frequency trace around crystal circuit.
- Ensure that the ground for the bypass capacitors is connected to a solid ground trace.
- Tie the ground trace to the ground pin nearest EXTAL and XTAL. This prevents large loop currents in the vicinity of the crystal.
- Tie the ground pin to the most solid ground in the system.
- Do not connect the trace that connects the oscillator and the ground plane to any other circuit element. This tends to make the oscillator unstable.
- Tie XTAL to ground when an external oscillator is clocking the device.

5.7 Interface Recommendations

5.7.1 SDRAM Controller

5.7.1.1 SDRAM Controller Signals in Synchronous Mode

Table 3 shows the behavior of SDRAM signals in synchronous mode.

Table 3. Synchronous DRAM Signal Connections

Signal	Description
SD_SRAS	Synchronous row address strobe. Indicates a valid SDRAM row address is present and can be latched by the SDRAM. $\overline{SD_SRAS}$ should be connected to the corresponding SDRAM $\overline{SD_SRAS}$. Do not confuse $\overline{SD_SRAS}$ with the DRAM controller's $\overline{SD_CS}$ [1:0], which should not be interfaced to the SDRAM $\overline{SD_SRAS}$ signals.
SD_SCAS	Synchronous column address strobe. Indicates a valid column address is present and can be latched by the SDRAM. $\overline{\text{SD_SCAS}}$ should be connected to the corresponding signal labeled $\overline{\text{SD_SCAS}}$ on the SDRAM.
DRAMW	DRAM read/write. Asserted for write operations and negated for read operations.
SD_CS[1:0]	Row address strobe. Select each memory block of SDRAMs connected to the MCF523x. One SD_CS signal selects one SDRAM block and connects to the corresponding CS signals.
SD_CKE	Synchronous DRAM clock enable. Connected directly to the CKE (clock enable) signal of SDRAMs. Enables and disables the clock internal to SDRAM. When CKE is low, memory can enter a power-down mode where operations are suspended or they can enter self-refresh mode. SD_CKE functionality is controlled by DCR[COC]. For designs using external multiplexing, setting COC allows SD_CKE to provide command-bit functionality.
BS[3:0]	Column address strobe. For synchronous operation, BS[3:0] function as byte enables to the SDRAMs. They connect to the DQM signals (or mask qualifiers) of the SDRAMs.
CLKOUT	Bus clock output. Connects to the CLK input of SDRAMs.

5.7.1.2 Address Multiplexing

See the SDRAM controller module chapter in the *MCF5235 Reference Manual* for details on address multiplexing.

5.7.2 Ethernet PHY Transceiver Connection

The FEC supports both an MII interface for 10/100 Mbps Ethernet and a seven-wire serial interface for 10 Mbps Ethernet. The interface mode is selected by R_CNTRL[MII_MODE]. In MII mode, the 802.3 standard defines and the FEC module supports 18 signals. These are shown in Table 4.

Table 4. MII Mode

Signal Description	MCF523x Pin
Transmit clock	ETXCLK
Transmit enable	ETXEN
Transmit data	ETXD[3:0]

MCF523x Integrated Microprocessor Hardware Specification, Rev. 4

Table 4. MII Mode (continued)

Signal Description	MCF523x Pin
Transmit error	ETXER
Collision	ECOL
Carrier sense	ECRS
Receive clock	ERXCLK
Receive enable	ERXDV
Receive data	ERXD[3:0]
Receive error	ERXER
Management channel clock	EMDC
Management channel serial data	EMDIO

The serial mode interface operates in what is generally referred to as AMD mode. The MCF523*x* configuration for seven-wire serial mode connections to the external transceiver are shown in Table 5.

Table 5. Seven-Wire Mode Configuration

Signal Description	MCF523x Pin
Transmit clock	ETXCLK
Transmit enable	ETXEN
Transmit data	ETXD[0]
Collision	ECOL
Receive clock	ERXCLK
Receive enable	ERXDV
Receive data	ERXD[0]
Unused, configure as PB14	ERXER
Unused input, tie to ground	ECRS
Unused, configure as PB[13:11]	ERXD[3:1]
Unused output, ignore	ETXER
Unused, configure as PB[10:8]	ETXD[3:1]
Unused, configure as PB15	EMDC
Input after reset, connect to ground	EMDIO

Refer to the M523*x*EVB evaluation board user's manual for an example of how to connect an external PHY. Schematics for this board are accessible at the MCF523*5* site by navigating to: http://www.freescale.com/coldfire.

Mechanicals/Pinouts and Part Numbers

5.7.3 FlexCAN

The FlexCAN module interface to the CAN bus is composed of 2 pins: CANTX and CANRX, which are the serial transmitted data and the serial received data. The use of an external CAN transceiver to interface to the CAN bus is generally required. The transceiver is capable of driving the large current needed for the CAN bus and has current protection, against a defective CAN bus or defective stations.

5.7.4 BDM

Use the BDM interface as shown in the M523*x*EVB evaluation board user's manual. The schematics for this board are accessible at the Freescale website at: http://www.freescale.com/coldfire.

6 Mechanicals/Pinouts and Part Numbers

This section contains drawings showing the pinout and the packaging and mechanical characteristics of the MCF523x devices. See Table 2 for a list the signal names and pin locations for each device.

6.1 Pinout—196 MAPBGA

The following figure shows a pinout of the MCF5232CVMxxx package.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	_
Α		TPUCH6	TPUCH3	TPUCH2	QSPI_ DOUT	QSPI_CS0	U2RXD	U2TXD	CS3	CS6	CS4	A20	A17		А
В	TPUCH8	TPUCH7	TPUCH4	TPUCH0	QSPI_ DIN	BS3	QSPI_CS1	U1CTS	CS7	CS1	A23	A19	A16	A15	В
С	TPUCH10	TPUCH9	TPUCH5	TPUCH1	QSPI_CLK	BS2	BS0	U1RTS	CS2	CS5	A22	A18	A14	A13	С
D	TPUCH13	TPUCH12	TPUCH11	NC	NC	VDD	BS1	U1RXD/ CANORX	U1TXD/ CAN0TX	CS0	A21	A12	A11	A10	D
Е	TPUCH14	TPUCH15	TCRCLK	DT0IN	OVDD	VSS	OVDD	SD_CKE	VSS	OVDD	А9	A8	A7	A6	Е
F	U0TXD	U0RXD	U0CTS	DT0OUT	TEST		OVDD	VSS	OVDD	VSS	VDD	A 5	A4	A3	F
G	D31	D30	U0RTS	VDD	CLKMOD1	OVDD	VSS	OVDD	VSS	LTPU ODIS	A2	A1	A0	DT3OUT	G
Н	D29	D28	D27	D26	CLKMOD0	VSS	OVDD	OVDD	OVDD	UTPU ODIS	TA	TIP	TS	DT3IN	Н
J	D25	D24	D23	D22	VSS	OVDD	VSS	OVDD	VSS	OVDD	I2C_SCL	I2C_SDA	R/W	TEA	J
K	D21	D20	D19	D18	OVDD	OVDD		OVDD	JTAG_EN	RCON	SD_SRAS	SD_SCAS	SD_WE	CLKOUT	К
L	D17	D16	D10	VDD	D3	DT1IN	ĪRQ5	ĪRQ1	DT2OUT	PST0	DDATA0	SD_CS1	SD_CS0	VSSPLL	L
М	D15	D13	D9	D6	D2	DT1OUT	ĪRQ6	ĪRQ2	DT2IN	TDI/DSI	PST3	DDATA3	VDDPLL	EXTAL	М
N	D14	D12	D8	D5	D1	ŌĒ	ĪRQ7	ĪRQ3	TRST/ DSCLK	TDO/DSO	PST2	DDATA2	RESET	XTAL	N
Р	VSS	D11	D7	D4	D0	TSIZ1	TSIZ0	ĪRQ4	TCLK/ PSTCLK	TMS/ BKPT	PST1	DDATA1	RSTOUT	VSS	Р
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	•

Figure 2. MCF5232CVMxxx Pinout (196 MAPBGA)

6.2 Package Dimensions—196 MAPBGA

Figure 3 shows MCF5232CVMxxx package dimensions.

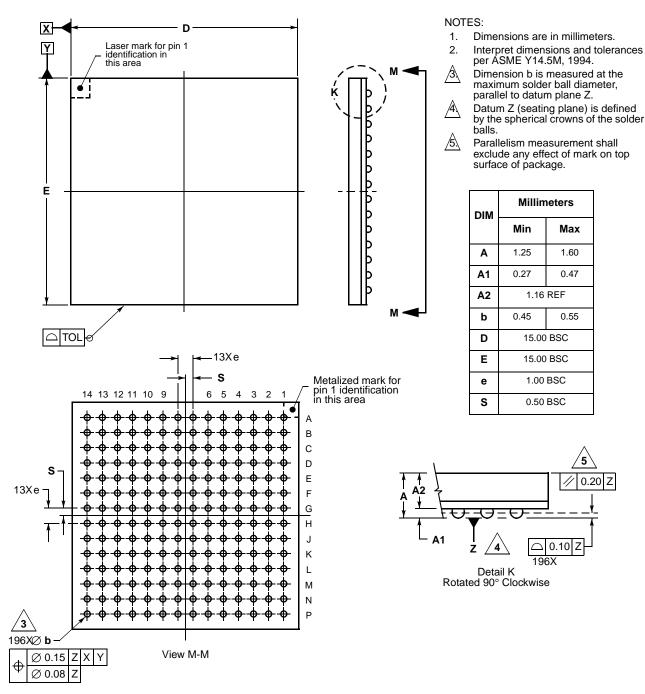


Figure 3. 196 MAPBGA Package Dimensions (Case No. 1128A-01)

Because of an order from the United States International Trade Commission, BGA-packaged product lines and part numbers indicated here currently are not available from Freescale for import or sale in the United States prior to September 2010: MCF523x products in 196 MAPBGA and 256 MAPBGA packages

6.2.1 Pinout—256 MAPBGA

Figure 4 through Figure 6 show pinouts of the MCF5233CVMxxx, MCF5234CVMxxx, and MCF5235CVMxxx packages.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	.
Α	VSS	TPUCH6	TPUCH4	TPUCH2	TPUCH17	TPUCH1	TPUCH0	VDD	BS1	BS0	U1RXD/ CAN0RX	U1TXD/ CAN0TX	CS6	CS4	A21	VSS	Α
В	TPUCH8	TPUCH7	TPUCH5	TPUCH3	TPUCH18	TPUCH19	TPUCH16	QSPI_ CLK	BS2	QSPI_ CS1	U1RTS	CS3	CS1	A23	A20	A19	в:
С	TPUCH10	TPUCH9	TPUCH25	TPUCH24	TPUCH22	TPUCH20	I2C_SDA/ U2RXD	QSPI_ DIN	BS3	SD_CKE	U1CTS	CS7	CS5	A22	A18	A17	B :
D	TPUCH12	TPUCH11	TPUCH27	TPUCH26	TPUCH23	TPUCH21	I2C_SCL/ U2TXD	QSPI_ DOUT	QSPI_ CS0	U2RXD/ CAN1RX	U2TXD/ CAN1TX	CS2	CS0	A14	A15	A16	D .
Е	TPUCH14	TPUCH13	TPUCH29	TPUCH28	VSS	OVDD	OVDD	OVDD	OVDD	OVDD	OVDD	VSS	A10	A11	A12	A13	E .
F	TCRCLK	TPUCH15	TPUCH31	TPUCH30	OVDD	VSS	OVDD	OVDD	OVDD	OVDD	VSS	OVDD	A7	A8	А9	VSS	F :
G	U0CTS	U0RXD	DT0OUT	DTOIN	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	A4	A 5	A6	VDD	G.
Η	VDD	U0TXD	U0RTS	NC	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	A0	A1	A2	A3	н.
J	VSS	CLK MOD0	CLK MOD1	TEST	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	UTPU ODIS	LTPU ODIS	DT3IN	DT3OUT	
K	D28	D29	D30	D31	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	TEA	TA	TIP	TS	К
L	D24	D25	D26	D27	OVDD	VSS	OVDD	OVDD	OVDD	OVDD	VSS	OVDD	SD_WE	I2C_SCL/ CAN0TX	I2C_SDA/ CANORX	R/W	L .
М	D21	D22	D23	NC	VSS	OVDD	OVDD	OVDD	OVDD	OVDD	OVDD	VSS	SD_ CS0	SD_ SRAS	SD_ SCAS	CLKOUT	M :
N	D19	D20	D13	D9	NC	D3	D0	TSIZ1	IRQ5	ĪRQ1	TRST/ DSCLK	PST0	JTAG_ EN	DDATA3	SD_CS1	VSS	N -
Р	D17	D18	D12	D8	D5	D2	DT1IN	TSIZ0	ĪRQ4	DT2IN	TMS/ BKPT	PST1	RCON	DDATA2	VDDPLL	EXTAL	
R	D16	D15	D11	D7	D4	D1	DT10UT	ĪRQ7	ĪRQ3	DT2OUT	TDO/ DSO	PST2	DDATA0	PLL_ TEST	VSSPLL	XTAL	
Т	VSS	D14	D10	D6	VDD	VSS	ŌĒ	ĪRQ6	ĪRQ2	TCLK/ PSTCLK	TDI/DSI	PST3	DDATA1	RSTOUT	RESET	VSS	T .
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	\square

Figure 4. MCF5233CVMxxx Pinout (256 MAPBGA)

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	
Α	VSS	TPUCH6	TPUCH4	TPUCH2	ETXD1	TPUCH1	TPUCH0	VDD	BS1	BS0	U1RXD/ CAN0RX	U1TXD/ CAN0TX	CS6	CS4	A21	VSS	А
В	TPUCH8	TPUCH7	TPUCH5	TPUCH3	ETXD2	ETXD3	ETXD0	QSPI_ CLK	BS2	QSPI_ CS1	U1RTS	CS3	CS1	A23	A20	A19	В
С	TPUCH10	TPUCH9	ERXD1	ERXD0	ETXCLK	ETXER	EMDIO	QSPI_ DIN	BS3	SD_CKE	U1CTS	CS7	CS5	A22	A18	A17	С
D	TPUCH12	TPUCH11	ERXD3	ERXD2	ERXER	ETXEN	EMDC	QSPI_ DOUT	QSPI_ CS0	U2RXD	U2TXD	CS2	CS0	A14	A15	A16	D
Е	TPUCH14	TPUCH13	ERXCLK	ERXDV	VSS	OVDD	OVDD	OVDD	OVDD	OVDD	OVDD	VSS	A10	A11	A12	A13	Е
F	TCRCLK	TPUCH15	ECOL	ECRS	OVDD	VSS	OVDD	OVDD	OVDD	OVDD	VSS	OVDD	A7	A8	А9	VSS	F
G	U0CTS	U0RXD	DT0OUT	DT0IN	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	A4	A5	A6	VDD	G
Н	VDD	U0TXD	UORTS	NC	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	A0	A1	A2	A3	н
J	VSS	CLK MOD0	CLK MOD1	TEST	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	UTPU ODIS	LTPU ODIS	DT3IN	DT3OUT	J
К	D28	D29	D30	D31	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	TEA	TA	TIP	TS	к
L	D24	D25	D26	D27	OVDD	VSS	OVDD	OVDD	OVDD	OVDD	VSS	OVDD	SD_WE	I2C_SCL/ CAN0TX	I2C_SDA/ CANORX	R/W	L
М	D21	D22	D23	NC	VSS	OVDD	OVDD	OVDD	OVDD	OVDD	OVDD	VSS	SD_CS0	SD_ SRAS	SD_ SCAS	CLKOUT	М
N	D19	D20	D13	D9	NC	D3	D0	TSIZ1	IRQ5	ĪRQ1	TRST/ DSCLK	PST0	JTAG_ EN	DDATA3	SD_CS1	VSS	N
Р	D17	D18	D12	D8	D5	D2	DT1IN	TSIZ0	IRQ4	DT2IN	TMS/ BKPT	PST1	RCON	DDATA2	VDDPLL	EXTAL	Р
R	D16	D15	D11	D7	D4	D1	DT1OUT	ĪRQ7	ĪRQ3	DT2OUT	TDO/ DSO	PST2	DDATA0	PLL_ TEST	VSSPLL	XTAL	R
Т	VSS	D14	D10	D6	VDD	VSS	ŌĒ	ĪRQ6	ĪRQ2	TCLK/ PSTCLK	TDI/DSI	PST3	DDATA1	RST OUT	RESET	VSS	Т
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	

Figure 5. MCF5234CVMxxx Pinout (256 MAPBGA)

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	
Α	VSS	TPUCH6	TPUCH4	TPUCH2	TPUCH17/ ETXD1	TPUCH1	TPUCH0	VDD	BS1	BS0	U1RXD/ CAN0RX	U1TXD/ CAN0TX	CS6	CS4	A21	VSS	Α
В	TPUCH8	TPUCH7	TPUCH5	TPUCH3	TPUCH18/ ETXD2	TPUCH19/ ETXD3	TPUCH16/ ETXD0	QSPI_ CLK	BS2	QSPI_ CS1	U1RTS	CS3	CS1	A23	A20	A19	В
С	TPUCH10	TPUCH9	TPUCH25/ ERXD1	TPUCH24/ ERXD0	TPUCH22/ ETXCLK	TPUCH20/ ETXER	I2C_SDA/ U2RXD/ EMDIO	QSPI_ DIN	BS3	SD_CKE	Ū1CTS	CS7	CS5	A22	A18	A17	С
D	TPUCH12	TPUCH11	TPUCH27/ ERXD3	TPUCH26/ ERXD2	TPUCH23/ ERXER	TPUCH21/ ETXEN	I2C_SCL/ U2TXD/ EMDC	QSPI_ DOUT	QSPI_ CS0	U2RXD/ CAN1RX	U2TXD/ CAN1TX	CS2	CS0	A14	A15	A16	D
Е	TPUCH14	TPUCH13	TPUCH29/ ERXCLK	TPUCH2/ ERXDV	VSS	OVDD	OVDD	OVDD	OVDD	OVDD	OVDD	VSS	A10	A11	A12	A13	Е
F	TCRCLK	TPUCH15	TPUCH31/ ECOL	TPUCH30/ ECRS	OVDD	VSS	OVDD	OVDD	OVDD	OVDD	VSS	OVDD	A7	A8	А9	VSS	F
G	U0CTS	U0RXD	DT0OUT	DTOIN	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	A4	A5	A6	VDD	G
Η	VDD	U0TXD	U0RTS	NC	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	A0	A1	A2	A3	Н
J	VSS	CLK MOD0	CLK MOD1	TEST	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	UTPU ODIS	LTPU ODIS	DT3IN	DT3OUT	J
K	D28	D29	D30	D31	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	TEA	TA	TIP	TS	K
L	D24	D25	D26	D27	OVDD	VSS	OVDD	OVDD	OVDD	OVDD	VSS	OVDD	SD_WE	I2C_SCL/ CAN0TX	I2C_SDA/ CAN0RX	R/W	L
М	D21	D22	D23	eTPU/ EthENB	VSS	OVDD	OVDD	OVDD	OVDD	OVDD	OVDD	VSS	SD_CS0	SD_ SRAS	SD_ SCAS	CLKOUT	М
Ν	D19	D20	D13	D9	NC	D3	D0	TSIZ1	IRQ5	IRQ1	TRST/ DSCLK	PST0	JTAG_ EN	DDATA3	SD_CS1	VSS	N
Р	D17	D18	D12	D8	D5	D2	DT1IN	TSIZ0	ĪRQ4	DT2IN	TMS/ BKPT	PST1	RCON	DDATA2	VDDPLL	EXTAL	Р
R	D16	D15	D11	D7	D4	D1	DT1OUT	IRQ7	IRQ3	DT2OUT	TDO/ DSO	PST2	DDATA0	PLL_ TEST	VSSPLL	XTAL	R
Т	VSS	D14	D10	D6	VDD	VSS	ŌĒ	IRQ6	IRQ2	TCLK/ PSTCLK	TDI/DSI	PST3	DDATA1	RSTOUT	RESET	VSS	Т
•	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	

Figure 6. MCF5235CVMxxx Pinout (256 MAPBGA)

6.2.2 Package Dimensions—256 MAPBGA

Figure 7 shows MCF5235CVMxxx, MCF5234CVMxxx, and MCF5233CVMxx package dimensions.

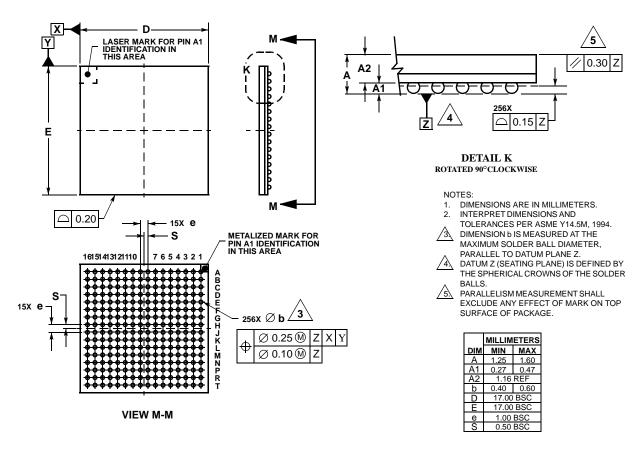


Figure 7. 256 MAPBGA Package Outline

6.3 Pinout—160 QFP

Figure 8 shows a pinout of the MCF5232CABxxx package.

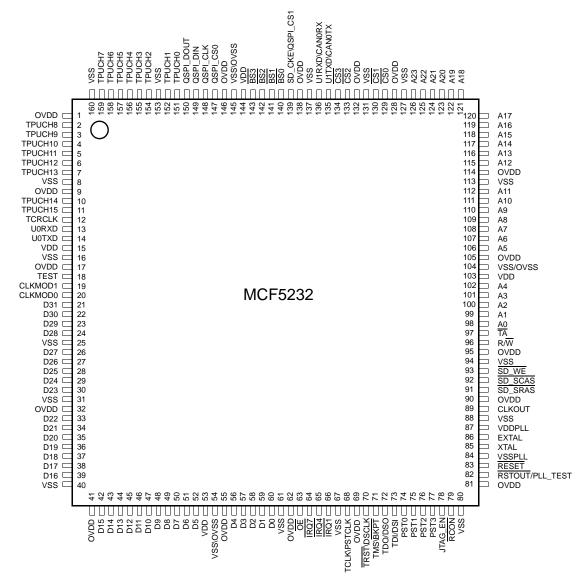
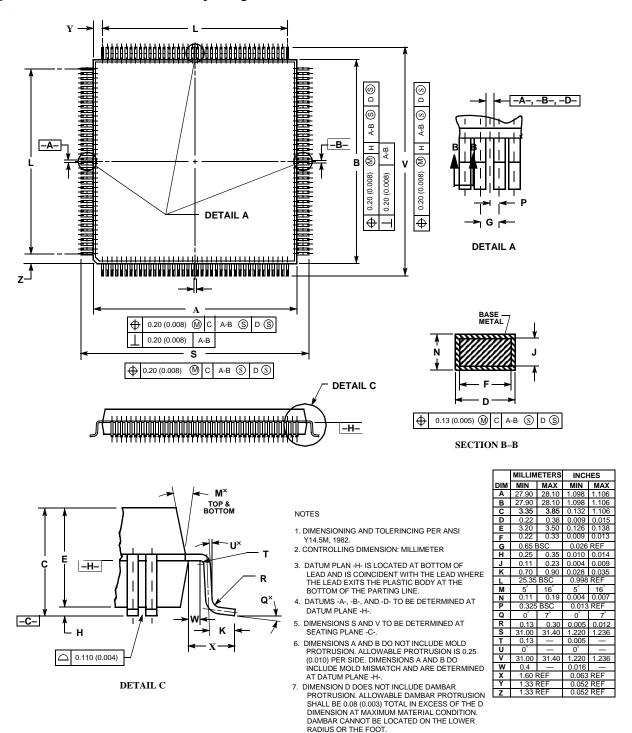


Figure 8. MCF5232CABxxx Pinout (160 QFP)

Freescale Semiconductor

6.4 Package Dimensions—160 QFP

Figure 9 shows MCF5232CAB80 package dimensions.



Case 864A-03

Figure 9. 160 QFP Package Dimensions

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6.5 Ordering Information

Table 6. Orderable Part Numbers

Freescale Part Number	Description	Package	Speed	Lead-Free?	Temperature
MCF5232CAB80	MCF5232 RISC Microprocessor	160 QFP	80MHz	Yes	-40° to +85° C
MCF5232CVM100	MCF5232 RISC Microprocessor	196 MAPBGA	100MHz	Yes	−40° to +85° C
MCF5232CVM150	MCF5232 RISC Microprocessor	196 MAPBGA	150MHz	Yes	−40° to +85° C
MCF5233CVM100	MCF5233 RISC Microprocessor	256 MAPBGA	100MHz	Yes	−40° to +85° C
MCF5233CVM150	MCF5233 RISC Microprocessor	256 MAPBGA	150MHz	Yes	−40° to +85° C
MCF5234CVM100	MCF5234 RISC Microprocessor	256 MAPBGA	100MHz	Yes	−40° to +85° C
MCF5234CVM150	MCF5234 RISC Microprocessor	256 MAPBGA	150MHz	Yes	−40° to +85° C
MCF5235CVM100	MCF5235 RISC Microprocessor	256 MAPBGA	100MHz	Yes	−40° to +85° C
MCF5235CVM150	MCF5235 RISC Microprocessor	256 MAPBGA	150MHz	Yes	-40° to +85° C
MCF5235CVF150	MCF5235 RISC Microprocessor,	256 MAPBGA	150MHz	No	-40° to +85° C

7 Electrical Characteristics

This chapter contains electrical specification tables and reference timing diagrams for the MCF5235 microcontroller unit. This section contains detailed information on power considerations, DC/AC electrical characteristics, and AC timing specifications of MCF5235.

NOTE

The parameters specified in this processor document supersede any values found in the module specifications.

7.1 Maximum Ratings

Table 7. Absolute Maximum Ratings^{1, 2}

Rating	Symbol	Value	Unit
Core Supply Voltage	V_{DD}	- 0.5 to +2.0	V
Pad Supply Voltage	OV _{DD}	- 0.3 to +4.0	V
PLL Supply Voltage	V _{DDPLL}	- 0.3 to +4.0	V
Digital Input Voltage ³	V _{IN}	- 0.3 to + 4.0	V
Instantaneous Maximum Current Single pin limit (applies to all pins) 3,4,5	I _D	25	mA
Operating Temperature Range (Packaged)	T _A (T _L - T _H)	- 40 to 85	°C
Storage Temperature Range	T _{stg}	- 65 to 150	°C

- Functional operating conditions are given in DC Electrical Specifications. Absolute Maximum Ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Continued operation at these levels may affect device reliability or cause permanent damage to the device.
- This device contains circuitry protecting against damage due to high static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (e.g., either V_{SS} or OV_{DD}).
- Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the larger of the two values.
- ⁴ All functional non-supply pins are internally clamped to V_{SS} and OV_{DD}.
- Power supply must maintain regulation within operating OV_{DD} range during instantaneous and operating maximum current conditions. If positive injection current (V_{in} > OV_{DD}) is greater than I_{DD}, the injection current may flow out of OV_{DD} and could result in external power supply going out of regulation. Insure external OV_{DD} load will shunt current greater than maximum injection current. This will be the greatest risk when the processor is not consuming power (ex; no clock). Power supply must maintain regulation within operating OV_{DD} range during instantaneous and operating maximum current conditions.

7.2 Thermal Characteristics

The below table lists thermal resistance values.

Table 8. Thermal Characteristics

Characteristic		Symbol	256 MAPBGA	196 MAPBGA	160 QFP	Unit
Junction to ambient, natural convection	Four layer board (2s2p)	θ_{JMA}	26 ^{1,2}	32 ^{1,2}	40 ^{1,2}	°C/W
Junction to ambient (@200 ft/min)	Four layer board (2s2p)	θ_{JMA}	23 ^{1,2}	29 ^{1,2}	36 ^{1,2}	°C/W
Junction to board		$\theta_{\sf JB}$	15 ³	20 ³	25 ³	°C/W
Junction to case		θ _{JC}	10 ⁴	10 ⁴	10 ⁴	°C/W
Junction to top of package		Ψ _{jt}	2 ^{1,5}	2 ^{1,5}	2 ^{1,5}	°C/W
Maximum operating junction temperature		Tj	102	104	105 ⁶	οС

 $[\]theta_{\text{JMA}}$ and Ψ_{jt} parameters are simulated in conformance with EIA/JESD Standard 51-2 for natural convection. Freescale recommends the use of θ_{JmA} and power dissipation specifications in the system design to prevent device junction temperatures from exceeding the rated specification. System designers should be aware that device junction temperatures can be significantly influenced by board layout and surrounding devices. Conformance to the device junction temperature specification can be verified by physical measurement in the customer's system using the Ψ_{jt} parameter, the device power dissipation, and the method described in EIA/JESD Standard 51-2.

- Per JEDEC JESD51-6 with the board horizontal.
- Thermal resistance between the die and the printed circuit board in conformance with JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
- ⁴ Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
- Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written in conformance with Psi-JT.
- ⁶ At 100MHz.

The average chip-junction temperature (T_J) in ${}^{\circ}C$ can be obtained from:

$$\Gamma_{\rm J} = \Gamma_{\rm A} + (P_{\rm D} \times \Theta_{\rm JMA})$$
 (1)

Where:

 T_A = Ambient Temperature, °C

 Θ_{JMA} = Package Thermal Resistance, Junction-to-Ambient, °C/W

$$P_D = P_{INT} + P_{I/O}$$

 $P_{INT} = I_{DD} \times V_{DD}$, Watts - Chip Internal Power

P_{I/O}= Power Dissipation on Input and Output Pins — User Determined

For most applications $P_{I/O} < P_{INT}$ and can be ignored. An approximate relationship between P_D and T_I (if $P_{I/O}$ is neglected) is:

$$P_D = K \div (T_J + 273^{\circ}C)$$
 (2)

Solving equations 1 and 2 for K gives:

$$K = P_D \times (T_A + 273 \,^{\circ}C) + \Theta_{JMA} \times P_D^2$$
 (3)

where K is a constant pertaining to the particular part. K can be determined from equation (3) by measuring P_D (at equilibrium) for a known T_A . Using this value of K, the values of P_D and P_D and P_D are obtained by solving equations (1) and (2) iteratively for any value of P_D .

7.3 DC Electrical Specifications

Table 9. DC Electrical Specifications¹

Characteristic	Symbol	Min	Typical	Max	Unit
Core Supply Voltage	V_{DD}	1.4	_	1.6	V
Pad Supply Voltage	OV _{DD}	3.0	_	3.6	V
PLL Supply Voltage	V_{DDPLL}	3.0	_	3.6	V
Input High Voltage	V _{IH}	$0.7 \times \text{OV}_{\text{DD}}$	_	3.65	V
Input Low Voltage	V _{IL}	V _{SS} - 0.3	_	$0.35 \times \text{OV}_{\text{DD}}$	V
Input Hysteresis	V _{HYS}	$0.06 \times \text{OV}_{\text{DD}}$	_	_	mV
Input Leakage Current V _{in} = V _{DD} or V _{SS} , Input-only pins	I _{in}	-1.0	_	1.0	μА
High Impedance (Off-State) Leakage Current $V_{in} = V_{DD}$ or V_{SS} , All input/output and output pins	I _{OZ}	-1.0	_	1.0	μА
Output High Voltage (All input/output and all output pins) I _{OH} = -5.0 mA	V _{OH}	OV _{DD} - 0.5	_	_	V
Output Low Voltage (All input/output and all output pins) I _{OL} = 5.0mA	V _{OL}	_	_	0.5	V
Weak Internal Pull Up Device Current, tested at V _{IL} Max. ²	I _{APU}	-10	_	- 130	μΑ

Table 9. DC Electrical Specifications¹ (continued)

Characteristic	Symbol	Min	Typical	Max	Unit
Input Capacitance ³ All input-only pins All input/output (three-state) pins	C _{in}		_	7 7	pF
Load Capacitance ⁴ Low drive strength High drive strength	C _L			25 50	pF pF
Core Operating Supply Current ⁵ Master Mode	I _{DD}	_	135	150	mA
Pad Operating Supply Current Master Mode Low Power Modes	Ol _{DD}		100 TBD		mA μA
DC Injection Current ^{3, 6, 7, 8} V _{NEGCLAMP} = V _{SS} - 0.3 V, V _{POSCLAMP} = V _{DD} + 0.3 Single Pin Limit Total processor Limit, Includes sum of all stressed pins	lic	-1.0 -10		1.0 10	mA mA

Refer to Table 10 for additional PLL specifications.

- ⁵ Current measured at maximum system clock frequency, all modules active, and default drive strength with matching load.
- ⁶ All functional non-supply pins are internally clamped to V_{SS} and their respective V_{DD}.
- Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the larger of the two values.
- Power supply must maintain regulation within operating V_{DD} range during instantaneous and operating maximum current conditions. If positive injection current ($V_{in} > V_{DD}$) is greater than I_{DD} , the injection current may flow out of V_{DD} and could result in external power supply going out of regulation. Insure external V_{DD} load will shunt current greater than maximum injection current. This will be the greatest risk when the processor is not consuming power. Examples are: if no system clock is present, or if clock rate is very low which would reduce overall power consumption. Also, at power-up, system clock is not present during the power-up sequence until the PLL has attained lock.

Refer to the MCF5235 signals section for pins having weak internal pull-up devices.

³ This parameter is characterized before qualification rather than 100% tested.

⁴ pF load ratings are based on DC loading and are provided as an indication of driver strength. High speed interfaces require transmission line analysis to determine proper drive strength and termination. See <u>High Speed Signal Propagation</u>: <u>Advanced Black Magic</u> by Howard W. Johnson for design guidelines.

7.4 Oscillator and PLLMRFM Electrical Characteristics

Table 10. HiP7 PLLMRFM Electrical Specifications¹

PLL Reference Frequency Range Crystal reference External reference 1:1 mode (NOTE: f _{sys/2} = 2 × f _{ref_1:1}) f _{sys}	Num	Characteristic	Symbol	Min. Value	Max. Value	Unit
CLKOUT Frequency 2 sys/2 f _{sys/2} 75 MHz MHz 3 Loss of Reference Frequency 3,5 f _{LOR} 100 1000 kHz 4 Self Clocked Mode Frequency 4,5 f _{SCM} 10.25 15.25 MHz 5 Crystal Start-up Time 5,6 t _{cst} — 10 ms 6 XTAL Load Capacitance ⁵ 5 30 pF 7 PLL Lock Time 5,7,13 t _{Ipll} — 750 µs 8 Power-up To Lock Time 5,6,8 With Crystal Reference (includes 5 time) Without Crystal Reference t _{Iplk} — 11 ms 9 1:1 Mode Clock Skew (between CLKOUT and EXTAL) t _{skew} —1 1 ns 10 Duty Cycle of reference 5 t _{dc} 40 60 % 11 Frequency Un-LOCK Range f _{LCK} —1.7 2.0 % f _{sys/2} 13 CLKOUT Period Jitter, 5, 6, 8, 11, 12 Measured at f _{sys/2} Max — 5.0 % f _{sys/2}	1	Crystal reference External reference	f _{ref_ext}	8	25	MHz
4 Self Clocked Mode Frequency ^{4, 5} f _{SCM} 10.25 15.25 MHz 5 Crystal Start-up Time ^{5, 6} t _{cst} — 10 ms 6 XTAL Load Capacitance ⁵ 5 30 pF 7 PLL Lock Time ^{5, 7,13} t _{lpll} — 750 μs 8 Power-up To Lock Time ^{5, 6,8} With Crystal Reference (includes 5 time) Without Crystal Reference 9 — 750 μs 9 1:1 Mode Clock Skew (between CLKOUT and EXTAL) 10	2	CLKOUT Frequency ² External reference	,	_	75	MHz
5 Crystal Start-up Time ^{5, 6} t _{cst} — 10 ms 6 XTAL Load Capacitance ⁵ 5 30 pF 7 PLL Lock Time ^{5, 7,13} t _{lpll} — 750 μs 8 Power-up To Lock Time ^{5, 6,8} With Crystal Reference (includes 5 time) Without Crystal Reference ⁹ — 750 μs 9 1:1 Mode Clock Skew (between CLKOUT and EXTAL) ¹⁰ ns 10 Duty Cycle of reference ⁵ t _{dc} 40 60 % 11 Frequency un-LOCK Range f _{LCK} — 1.7 2.0 % f _{sys/2} 12 Frequency LOCK Range f _{LCK} — 1.7 2.0 % f _{sys/2} 13 CLKOUT Period Jitter, ^{5, 6, 8,11, 12} Measured at f _{sys/2} Max Peak-to-peak Jitter (Clock edge to clock edge) Long Term Jitter (Averaged over 2 ms interval) 14 Frequency Modulation Range Limit ^{13,14} (f _{sys/2} Max must not be exceeded)	3	Loss of Reference Frequency ^{3, 5}	f_{LOR}	100	1000	kHz
6 XTAL Load Capacitance ⁵ 5 30 pF 7 PLL Lock Time ^{5, 7,13} t _{1pll} — 750 μs 8 Power-up To Lock Time ^{5, 6,8} With Crystal Reference (includes 5 time) Without Crystal Reference ⁹ — 11 ms 9 1:1 Mode Clock Skew (between CLKOUT and EXTAL) 10 Loty Cycle of reference 5 t _{dc} 40 60 % 11 Frequency un-LOCK Range f _{UL} —3.8 4.1 % f _{sys/2} 12 Frequency LOCK Range f _{LCK} —1.7 2.0 % f _{sys/2} 13 CLKOUT Period Jitter, ^{5, 6, 8,11, 12} Measured at f _{sys/2} Max Peak-to-peak Jitter (Clock edge to clock edge) Long Term Jitter (Averaged over 2 ms interval) 14 Frequency Modulation Range Limit 13.14 (f _{sys/2} Max must not be exceeded)	4	Self Clocked Mode Frequency ^{4, 5}	f _{SCM}	10.25	15.25	MHz
7 PLL Lock Time ^{5, 7,13}	5	Crystal Start-up Time ^{5, 6}	t _{cst}	_	10	ms
8	6	XTAL Load Capacitance ⁵		5	30	pF
With Crystal Reference (includes 5 time) — 11 ms μs 9 1:1 Mode Clock Skew (between CLKOUT and EXTAL) 10 t _{skew} —1 1 ns 10 Duty Cycle of reference 5 t _{dc} 40 60 % 11 Frequency un-LOCK Range f _{UL} —3.8 4.1 % f _{sys/2} 12 Frequency LOCK Range f _{LCK} —1.7 2.0 % f _{sys/2} 13 CLKOUT Period Jitter, ^{5, 6, 8,11, 12} Measured at f _{sys/2} Max Peak-to-peak Jitter (Clock edge to clock edge) Long Term Jitter (Averaged over 2 ms interval) — 5.0 % f _{sys/2} % f _{sys/2} 14 Frequency Modulation Range Limit ^{13,14} (f _{sys/2} Max must not be exceeded) C _{mod} 0.8 2.2 % f _{sys/2}	7	PLL Lock Time ^{5, 7,13}	t _{lpll}	_	750	μS
and EXTAL) 10 10 10 10 10 10 10 10	8	With Crystal Reference (includes 5 time)	t _{lplk}	_ _		_
11 Frequency un-LOCK Range 12 Frequency LOCK Range 13 CLKOUT Period Jitter, ^{5, 6, 8,11, 12} Measured at f _{sys/2} Max Peak-to-peak Jitter (Clock edge to clock edge) Long Term Jitter (Averaged over 2 ms interval) 14 Frequency Modulation Range Limit ^{13,14} (f _{sys/2} Max must not be exceeded) 15 CLKOUT Period Jitter, ^{5, 6, 8,11, 12} C _{jitter} 16 C _{jitter} 17 C _{jitter} 18 C _{jitter} 19 C _{jitter} 10 C _{jitter} 10 C _{jitter} 11 C _{jitter} 12 C _{jitter} 13 CLKOUT Period Jitter, ^{5, 6, 8,11, 12} C _{jitter} 14 C _{mod} 15 C _{jitter} 16 C _{jitter} 17 C _{jitter} 18 C _{jitter} 19 C _{jitter} 10 C _{jitter} 10 C _{jitter} 11 C _{jitter} 11 C _{jitter} 12 C _{jitter} 13 C _{jitter} 14 C _{mod} 15 C _{mod} 16 C _{mod} 17 C _{mod} 18 C _{sys/2} 18 C _{sys/2}	9		t _{skew}	-1	1	ns
12 Frequency LOCK Range 13 CLKOUT Period Jitter, ^{5, 6, 8,11, 12} Measured at f _{sys/2} Max Peak-to-peak Jitter (Clock edge to clock edge) Long Term Jitter (Averaged over 2 ms interval) 14 Frequency Modulation Range Limit ^{13,14} (f _{sys/2} Max must not be exceeded) 15 C _{jitter} 5.0 % f _{sys/2} 0.8 2.2 % f _{sys/2}	10	Duty Cycle of reference ⁵	t _{dc}	40	60	%
13 CLKOUT Period Jitter, ^{5, 6, 8,11, 12} Measured at f _{sys/2} Max Peak-to-peak Jitter (Clock edge to clock edge) Long Term Jitter (Averaged over 2 ms interval) 14 Frequency Modulation Range Limit ^{13,14} (f _{sys/2} Max must not be exceeded) C _{jitter} — 5.0 % f _{sys/2} — 0.1	11	Frequency un-LOCK Range	f _{UL}	-3.8	4.1	% f _{sys/2}
Measured at f _{sys/2} Max Peak-to-peak Jitter (Clock edge to clock edge) Long Term Jitter (Averaged over 2 ms interval) 14 Frequency Modulation Range Limit 13,14 (f _{sys/2} Max must not be exceeded)	12	Frequency LOCK Range	f _{LCK}	-1.7	2.0	% f _{sys/2}
(f _{sys/2} Max must not be exceeded)	13	Measured at f _{sys/2} Max Peak-to-peak Jitter (Clock edge to clock edge) Long Term Jitter (Averaged over 2 ms	C _{jitter}			% f _{sys/2}
15 ICO Frequency. $f_{ico} = f_{ref} \times 2 \times (MFD+2)^{15}$ f_{ico} 48 150 MHz	14	Frequency Modulation Range Limit ^{13,14} (f _{sys/2} Max must not be exceeded)	C _{mod}	0.8	2.2	%f _{sys/2}
	15	ICO Frequency. $f_{ico} = f_{ref} \times 2 \times (MFD+2)^{-15}$	f _{ico}	48	150	MHz

All values given are initial design targets and subject to change.

² All internal registers retain data at 0 Hz.

^{3 &}quot;Loss of Reference Frequency" is the reference frequency detected internally, which transitions the PLL into self clocked mode.

Self clocked mode frequency is the frequency that the PLL operates at when the reference frequency falls below f_{LOR} with default MFD/RFD settings.

⁵ This parameter is guaranteed by characterization before qualification rather than 100% tested.

⁶ Proper PC board layout procedures must be followed to achieve specifications.

- This specification applies to the period required for the PLL to relock after changing the MFD frequency control bits in the synthesizer control register (SYNCR).
- Assuming a reference is available at power up, lock time is measured from the time V_{DD} and V_{DDSYN} are valid to RSTOUT negating. If the crystal oscillator is being used as the reference for the PLL, then the crystal start up time must be added to the PLL lock time to determine the total start-up time.
- $t_{|p||} = (64 * 4 * 5 + 5 \times \tau) \times T_{ref}$, where $T_{ref} = 1/F_{ref_crystal} = 1/F_{ref_ext} = 1/F_{ref_1:1}$, and $\tau = 1.57 \times 10^{-6} \times 2 (MFD + 2)$.
- 10 PLL is operating in 1:1 PLL mode.
- Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum f_{sys/2}. Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the PLL circuitry via V_{DDSYN} and V_{SSSYN} and variation in crystal oscillator frequency increase the Cjitter percentage for a given interval.
- Values are with frequency modulation disabled. If frequency modulation is enabled, jitter is the sum of Cjitter+Cmod.
- ¹³ Modulation percentage applies over an interval of 10μs, or equivalently the modulation rate is 100KHz.
- Modulation rate selected must not result in f_{sys/2} value greater than the f_{sys/2} maximum specified value. Modulation range determined by hardware design.
- ¹⁵ $f_{\text{SVS/2}} = f_{\text{ico}} / (2 \cdot 2^{\text{RFD}})$

7.5 External Interface Timing Characteristics

Table 11 lists processor bus input timings.

NOTE

All processor bus timings are synchronous; that is, input setup/hold and output delay with respect to the rising edge of a reference clock. The reference clock is the CLKOUT output.

All other timing relationships can be derived from these values.

Table 11. Processor Bus Input Timing Specifications

Name	Characteristic ¹	Symbol	Min	Max	Unit
freq	System bus frequency	f _{sys/2}	50	75	MHz
В0	CLKOUT period	t _{cyc}	_	1/75	ns
	Control Inputs				
B1a	Control input valid to CLKOUT high ²	t _{CVCH}	9	_	ns
B1b	BKPT valid to CLKOUT high ³	t _{BKVCH}	9	_	ns
B2a	CLKOUT high to control inputs invalid ²	t _{CHCII}	0	_	ns
B2b	CLKOUT high to asynchronous control input BKPT invalid ³	t _{BKNCH}	0	_	ns
	Data Inputs				
B4	Data input (D[31:0]) valid to CLKOUT high	t _{DIVCH}	4	_	ns
B5	CLKOUT high to data input (D[31:0]) invalid	t _{CHDII}	0	_	ns

Timing specifications are tested using full drive strength pad configurations in a 50ohm transmission line environment..

² TEA and TA pins are being referred to as control inputs.

Refer to figure A-19.

Timings listed in Table 11 are shown in Figure 10.

* The timings are also valid for inputs sampled on the negative clock edge.

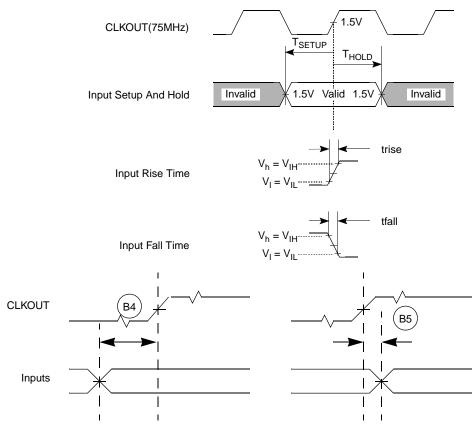


Figure 10. General Input Timing Requirements

7.6 Processor Bus Output Timing Specifications

Table 12 lists processor bus output timings.

Table 12. External Bus Output Timing Specifications

Name	Characteristic	Symbol	Min	Max	Unit
	Control Outputs				
В6а	CLKOUT high to chip selects valid ¹	t _{CHCV}	_	0.5t _{CYC} +5	ns
B6b	CLKOUT high to byte enables (BS[3:0]) valid ²	t _{CHBV}	_	0.5t _{CYC} +5	ns
B6c	CLKOUT high to output enable (OE) valid ³	t _{CHOV}	_	0.5t _{CYC} +5	ns
B7	CLKOUT high to control output (BS[3:0], OE) invalid	t _{CHCOI}	0.5t _{CYC} +1.5	_	ns
В7а	CLKOUT high to chip selects invalid	t _{CHCI}	0.5t _{CYC} +1.5	_	ns

Table 12. External Bus Output Timing Specifications (continued)

Name	Characteristic	Symbol	Min	Max	Unit
	Address and Attribute C	Outputs			
В8	CLKOUT high to address (A[23:0]) and control (TS, TSIZ[1:0], TIP, R/W) valid	t _{CHAV}	_	9	ns
B9	CLKOUT high to address (A[23:0]) and control (TS, TSIZ[1:0], TIP, R/W) invalid	t _{CHAI}	1.5	_	ns
	Data Outputs				
B11	CLKOUT high to data output (D[31:0]) valid	t _{CHDOV}	_	9	ns
B12	CLKOUT high to data output (D[31:0]) invalid	t _{CHDOI}	1.5	_	ns
B13	CLKOUT high to data output (D[31:0]) high impedance	t _{CHDOZ}	_	9	ns

Temperature 1 Temperature 1 Temperature 1 Temperature 2 Temperature 2

² BS transitions after the falling edge of CLKOUT.

³ OE transitions after the falling edge of CLKOUT.

Read/write bus timings listed in Table 12 are shown in Figure 11, Figure 12, and Figure 13.

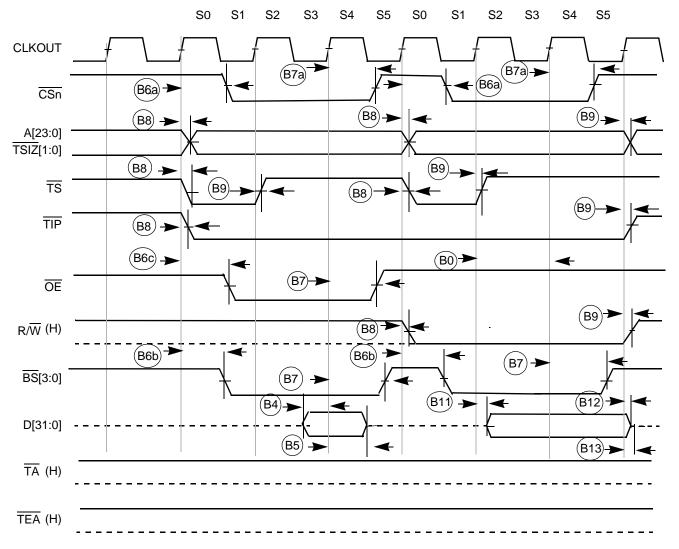


Figure 11. Read/Write (Internally Terminated) SRAM Bus Timing

Figure 12 shows a bus cycle terminated by \overline{TA} showing timings listed in Table 12.

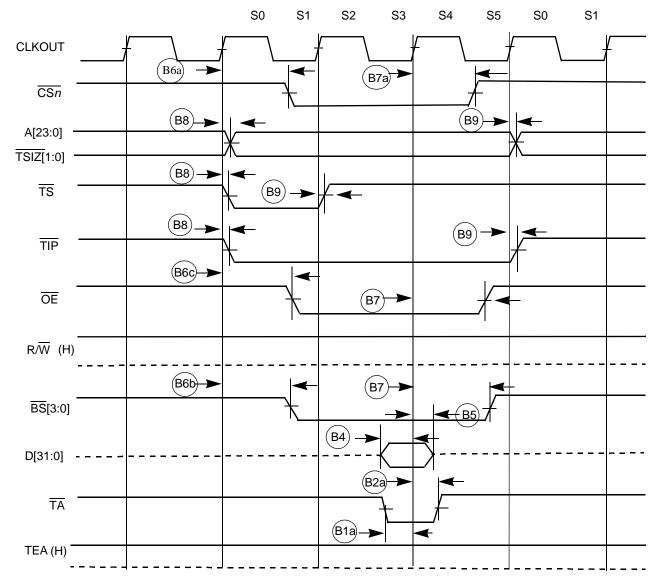


Figure 12. SRAM Read Bus Cycle Terminated by TA

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Figure 13 shows an SRAM bus cycle terminated by TEA showing timings listed in Table 12.

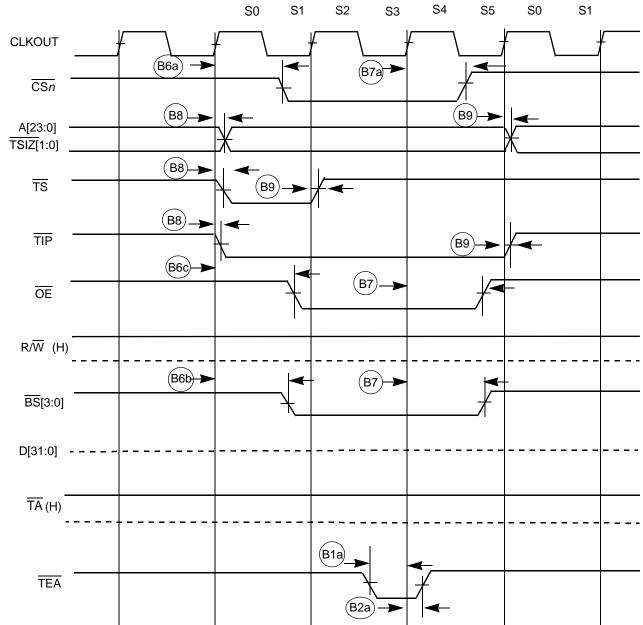


Figure 13. SRAM Read Bus Cycle Terminated by TEA

Figure 14 shows an SDRAM read cycle.

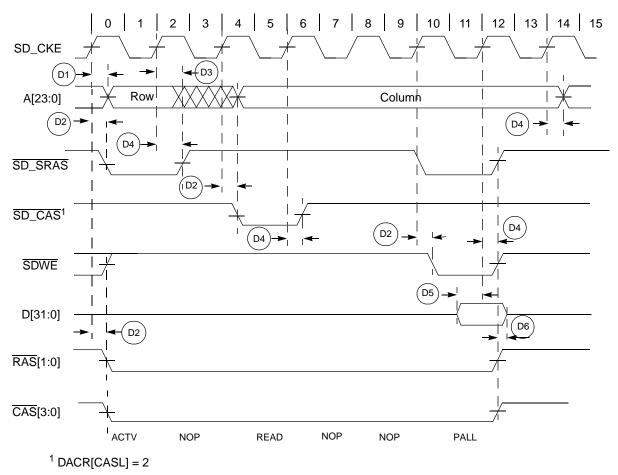


Figure 14. SDRAM Read Cycle

Table 13. SDRAM Timing

NUM	Characteristic	Symbol	Min	Max	Unit
D1	CLKOUT high to SDRAM address valid	t _{CHDAV}	_	9	ns
D2	CLKOUT high to SDRAM control valid	t _{CHDCV}	_	9	ns
D3	CLKOUT high to SDRAM address invalid	t _{CHDAI}	1.5	_	ns
D4	CLKOUT high to SDRAM control invalid	t _{CHDCI}	1.5	_	ns
D5	SDRAM data valid to CLKOUT high	t _{DDVCH}	4	_	ns
D6	CLKOUT high to SDRAM data invalid	t _{CHDDI}	1.5	_	ns
D7 ¹	CLKOUT high to SDRAM data valid	t _{CHDDVW}	_	9	ns
D8 ¹	CLKOUT high to SDRAM data invalid	t _{CHDDIW}	1.5	_	ns

D7 and D8 are for write cycles only.

Figure 15 shows an SDRAM write cycle.

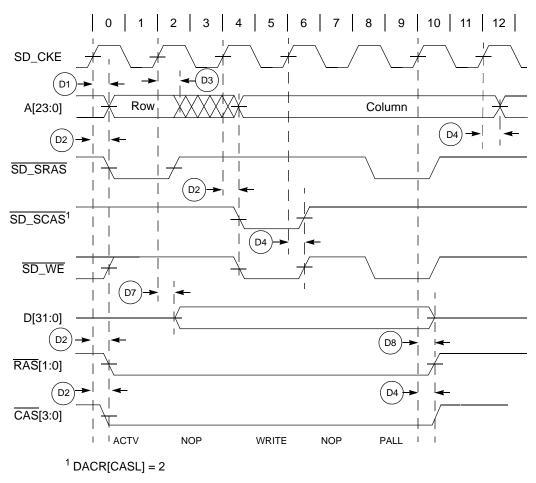


Figure 15. SDRAM Write Cycle

7.7 General Purpose I/O Timing

Table 14. GPIO Timing¹

NUM	Characteristic	Symbol	Min	Max	Unit
G1	CLKOUT High to GPIO Output Valid	t _{CHPOV}	_	10	ns
G2	CLKOUT High to GPIO Output Invalid	t _{CHPOI}	1.5	_	ns
G3	GPIO Input Valid to CLKOUT High	t _{PVCH}	9	_	ns
G4	CLKOUT High to GPIO Input Invalid	t _{CHPI}	1.5	_	ns

GPIO pins include: INT, ETPU, UART, FlexCAN, Timer, $\overline{\text{DREQ}n}$ and $\overline{\text{DACK}n}$ pins.

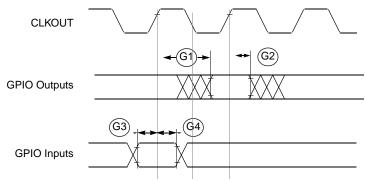


Figure 16. GPIO Timing

7.8 Reset and Configuration Override Timing

Table 15. Reset and Configuration Override Timing $(V_{DD} = 2.7 \text{ to } 3.6 \text{ V}, V_{SS} = 0 \text{ V}, T_A = T_L \text{ to } T_H)^1$

NUM	Characteristic	Symbol	Min	Max	Unit
R1	RESET Input valid to CLKOUT High	t _{RVCH}	9	_	ns
R2	CLKOUT High to RESET Input invalid	t _{CHRI}	1.5	_	ns
R3	RESET Input valid Time ²	t _{RIVT}	5	_	t _{CYC}
R4	CLKOUT High to RSTOUT Valid	t _{CHROV}	_	10	ns
R5	RSTOUT valid to Config. Overrides valid	t _{ROVCV}	0	_	ns
R6	Configuration Override Setup Time to RSTOUT invalid	t _{cos}	20	_	t _{CYC}
R7	Configuration Override Hold Time after RSTOUT invalid	t _{COH}	0	_	ns
R8	RSTOUT invalid to Configuration Override High Impedance	t _{ROICZ}	_	1	t _{CYC}

All AC timing is shown with respect to 50% V_{DD} levels unless otherwise noted.

During low power STOP, the synchronizers for the RESET input are bypassed and RESET is asserted asynchronously to the system. Thus, RESET must be held a minimum of 100 ns.

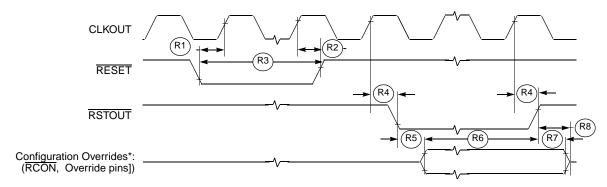


Figure 17. RESET and Configuration Override Timing

Refer to the chip configuration module (CCM) chapter in the device's reference manual for more information.

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7.9 I²C Input/Output Timing Specifications

Table 16 lists specifications for the I²C input timing parameters shown in Figure 18.

Table 16. I²C Input Timing Specifications between I2C_SCL and I2C_SDA

Num	Characteristic		Max	Units
I1	Start condition hold time	2	_	t _{cyc}
12	Clock low period	8	_	t _{cyc}
13	I2C_SCL/I2C_SDA rise time ($V_{IL} = 0.5 \text{ V to } V_{IH} = 2.4 \text{ V}$)	_	1	ms
14	Data hold time	0	_	ns
15	I2C_SCL/I2C_SDA fall time ($V_{IH} = 2.4 \text{ V to } V_{IL} = 0.5 \text{ V}$)	_	1	ms
16	Clock high time	4	_	t _{cyc}
17	Data setup time	0	_	ns
18	Start condition setup time (for repeated start condition only)	2	_	t _{cyc}
19	Stop condition setup time	2	_	t _{cyc}

Table 17 lists specifications for the I²C output timing parameters shown in Figure 18.

Table 17. I²C Output Timing Specifications between I2C_SCL and I2C_SDA

Num	Characteristic	Min	Max	Units
11 ¹	Start condition hold time	6	_	t _{cyc}
I2 ¹	Clock low period	10	_	t _{cyc}
I3 ²	I2C_SCL/I2C_SDA rise time ($V_{IL} = 0.5 \text{ V to } V_{IH} = 2.4 \text{ V}$)	_	_	μs
I4 ¹	Data hold time	7	_	t _{cyc}
I5 ³	I2C_SCL/I2C_SDA fall time ($V_{IH} = 2.4 \text{ V to } V_{IL} = 0.5 \text{ V}$)	_	3	ns
I6 ¹	Clock high time	10	_	t _{cyc}
I7 ¹	Data setup time	2	_	t _{cyc}
I8 ¹	Start condition setup time (for repeated start condition only)	20	_	t _{cyc}
I9 ¹	Stop condition setup time	10	_	t _{cyc}

Note: Output numbers depend on the value programmed into the IFDR; an IFDR programmed with the maximum frequency (IFDR = 0x20) results in minimum output timings as shown in Table 17. The I²C interface is designed to scale the actual data transition time to move it to the middle of the I2C_SCL low period. The actual position is affected by the prescale and division values programmed into the IFDR; however, the numbers given in Table 17 are minimum values.

Figure 18 shows timing for the values in Table 16 and Table 17.

Because I2C_SCL and I2C_SDA are open-collector-type outputs, which the processor can only actively drive low, the time I2C_SCL or I2C_SDA take to reach a high level depends on external signal capacitance and pull-up resistor values.

³ Specified at a nominal 50-pF load.

Electrical Characteristics

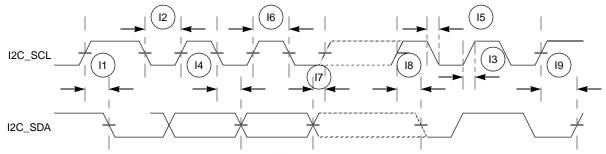


Figure 18. I²C Input/Output Timings

7.10 Fast Ethernet AC Timing Specifications

MII signals use TTL signal levels compatible with devices operating at either 5.0 V or 3.3 V.

7.10.1 MII Receive Signal Timing (ERXD[3:0], ERXDV, ERXER, and ERXCLK)

The receiver functions correctly up to a ERXCLK maximum frequency of 25 MHz +1%. The processor clock frequency must exceed twice the ERXCLK frequency.

Table 18 lists MII receive channel timings.

Table 18. MII Receive Signal Timing

Num	Characteristic	Min	Max	Unit
M1	ERXD[3:0], ERXDV, ERXER to ERXCLK setup	5	_	ns
M2	ERXCLK to ERXD[3:0], ERXDV, ERXER hold	5	_	ns
М3	ERXCLK pulse width high	35%	65%	ERXCLK period
M4	ERXCLK pulse width low	35%	65%	ERXCLK period

Figure 19 shows MII receive signal timings listed in Table 18.

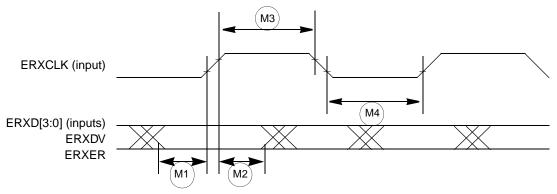


Figure 19. MII Receive Signal Timing Diagram

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7.10.2 MII Transmit Signal Timing (ETXD[3:0], ETXEN, ETXER, ETXCLK)

Table 19 lists MII transmit channel timings.

The transmitter functions correctly up to a ETXCLK maximum frequency of 25 MHz +1%. The processor clock frequency must exceed twice the ETXCLK frequency.

Table 19. MII Transmit Signal Timing

Num	Characteristic	Min	Max	Unit
M5	ETXCLK to ETXD[3:0], ETXEN, ETXER invalid	5	_	ns
M6	ETXCLK to ETXD[3:0], ETXEN, ETXER valid	_	25	ns
M7	ETXCLK pulse width high	35%	65%	ETXCLK period
M8	ETXCLK pulse width low	35%	65%	ETXCLK period

Figure 20 shows MII transmit signal timings listed in Table 19.

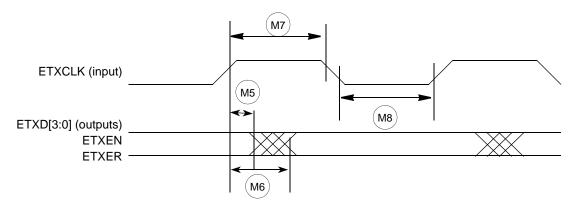


Figure 20. MII Transmit Signal Timing Diagram

7.10.3 MII Async Inputs Signal Timing (ECRS and ECOL)

Table 20 lists MII asynchronous inputs signal timing.

Table 20. MII Async Inputs Signal Timing

Num	Characteristic	Min	Max	Unit
M9	ECRS, ECOL minimum pulse width	1.5	l	ETXCLK period

Figure 21 shows MII asynchronous input timings listed in Table 20.



Figure 21. MII Async Inputs Timing Diagram

7.10.4 MII Serial Management Channel Timing (EMDIO and EMDC)

Table 21 lists MII serial management channel timings. The FEC functions correctly with a maximum MDC frequency of 2.5 MHz.

Table 21. MII Serial Management Channel Timing

Num	Characteristic		Max	Unit
M10	EMDC falling edge to EMDIO output invalid (minimum propagation delay)	0	_	ns
M11	EMDC falling edge to EMDIO output valid (max prop delay)	_	25	ns
M12	EMDIO (input) to EMDC rising edge setup	10	_	ns
M13	EMDIO (input) to EMDC rising edge hold	0	_	ns
M14	EMDC pulse width high	40%	60%	MDC period
M15	EMDC pulse width low	40%	60%	MDC period

Figure 22 shows MII serial management channel timings listed in Table 21.

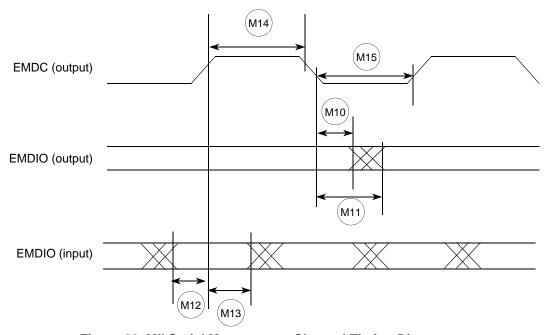


Figure 22. MII Serial Management Channel Timing Diagram

7.11 32-Bit Timer Module AC Timing Specifications

Table 22 lists timer module AC timings.

Table 22. Timer Module AC Timing Specifications

Name	Characteristic	0–66 MHz		0–66 MHz		Unit
Name	Gharacteristic	Min	Max	Oilit		
T1	DT0IN / DT1IN / DT2IN / DT3IN cycle time	3	_	t _{CYC}		
T2	DT0IN / DT1IN / DT2IN / DT3IN pulse width	1	_	t _{CYC}		

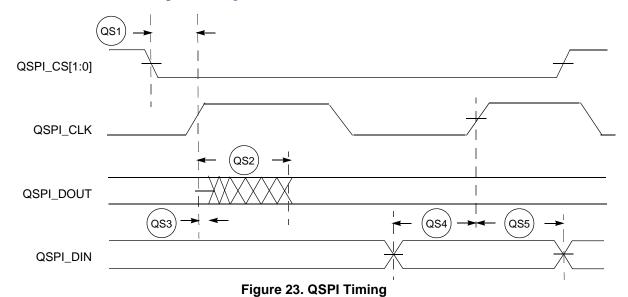
7.12 QSPI Electrical Specifications

Table 23 lists QSPI timings.

Table 23. QSPI Modules AC Timing Specifications

Name	Characteristic	Min	Max	Unit
QS1	QSPI_CS[1:0] to QSPI_CLK	1	510	tcyc
QS2	QSPI_CLK high to QSPI_DOUT valid.	_	10	ns
QS3	QSPI_CLK high to QSPI_DOUT invalid. (Output hold)	2	_	ns
QS4	QSPI_DIN to QSPI_CLK (Input setup)	9	_	ns
QS5	QSPI_DIN to QSPI_CLK (Input hold)	9	_	ns

The values in Table 23 correspond to Figure 23.



7.13 JTAG and Boundary Scan Timing

Table 24. JTAG and Boundary Scan Timing

Num	Characteristics ¹	Symbol	Min	Max	Unit
J1	TCLK Frequency of Operation	f _{JCYC}	DC	1/4	f _{sys/2}
J2	TCLK Cycle Period	t _{JCYC}	4	_	t _{CYC}
J3	TCLK Clock Pulse Width	t _{JCW}	26	_	ns
J4	TCLK Rise and Fall Times	t _{JCRF}	0	3	ns
J5	Boundary Scan Input Data Setup Time to TCLK Rise	t _{BSDST}	4	_	ns
J6	Boundary Scan Input Data Hold Time after TCLK Rise	t _{BSDHT}	26	_	ns
J7	TCLK Low to Boundary Scan Output Data Valid	t _{BSDV}	0	33	ns
J8	TCLK Low to Boundary Scan Output High Z	t _{BSDZ}	0	33	ns
J9	TMS, TDI Input Data Setup Time to TCLK Rise	t _{TAPBST}	4	_	ns
J10	TMS, TDI Input Data Hold Time after TCLK Rise	t _{TAPBHT}	10	_	ns
J11	TCLK Low to TDO Data Valid	t _{TDODV}	0	26	ns
J12	TCLK Low to TDO High Z	t _{TDODZ}	0	8	ns
J13	TRST Assert Time	t _{TRSTAT}	100	_	ns
J14	TRST Setup Time (Negation) to TCLK High	t _{TRSTST}	10	_	ns

JTAG_EN is expected to be a static signal. Hence, specific timing is not associated with it.

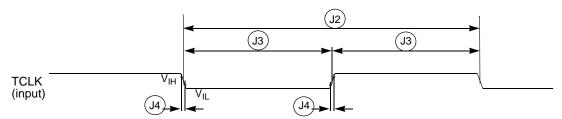


Figure 24. Test Clock Input Timing

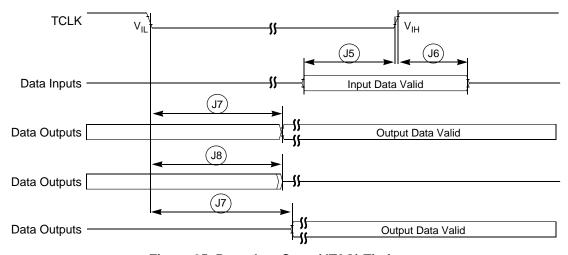


Figure 25. Boundary Scan (JTAG) Timing

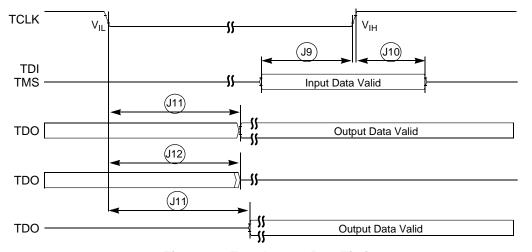


Figure 26. Test Access Port Timing

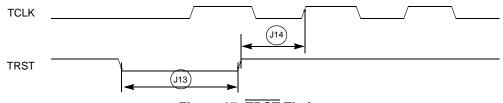


Figure 27. TRST Timing

7.14 Debug AC Timing Specifications

Table 25 lists specifications for the debug AC timing parameters shown in Figure 29.

Table 25. Debug AC Timing Specification

Num	Characteristic	150	MHz	Units	
Num	Gilalacteristic	Min	Max		
DE0	PSTCLK cycle time	_	0.5	t _{cyc}	
DE1	PST valid to PSTCLK high	4	_	ns	
DE2	PSTCLK high to PST invalid	1.5	_	ns	
DE3	DSCLK cycle time	5	_	t _{cyc}	
DE4	DSI valid to DSCLK high	1	_	t _{cyc}	
DE5 ¹	DSCLK high to DSO invalid	4	_	t _{cyc}	
DE6	BKPT input data setup time to CLKOUT rise	4	_	ns	
DE7	CLKOUT high to BKPT high Z	0	10	ns	

DSCLK and DSI are synchronized internally. D4 is measured from the synchronized DSCLK input relative to the rising edge of CLKOUT.

Figure 28 shows real-time trace timing for the values in Table 25.

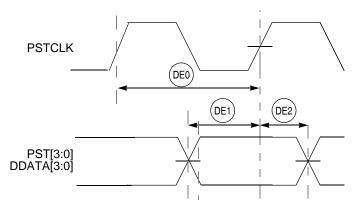


Figure 28. Real-Time Trace AC Timing

Figure 29 shows BDM serial port AC timing for the values in Table 25.

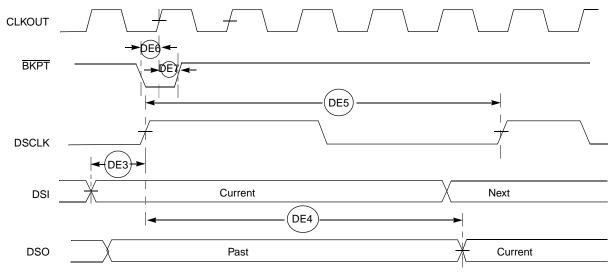


Figure 29. BDM Serial Port AC Timing

8 Documentation

Documentation regarding the MCF523*x* and their development support tools is available from a local Freescale distributor, a Freescale semiconductor sales office, the Freescale Literature Distribution Center, or through the Freescale web address at http://www.freescale.com/coldfire.

9 Document Revision History

The below table provides a revision history for this document.

Table 26. MCF5235EC Revision History

Rev. No.	Substantive Change(s)
0	Preliminary release.
1	Updated Signal List table
1.1	Removed duplicate information in the module description sections. The information is all in the Signals Description Table.
1.2	Corrected Figure 8 pin 81. VDD instead of VSS Changed instances of Motorola to Freescale
1.3	 Removed detailed signal description section. This information can be found in the MCF5235RM Chapter 2. Removed detailed feature list. This information can be found in the MCF5235RM Chapter 1. Corrected Figure 2 pin F10. VSS instead of VDD. Change made in Table 2 as well. Corrected Figure 8 pin 81. OVDD instead of VDD. Change made in Table 2 as well. Cleaned up many inconsistencies within the pinout figure signal names Corrected document IDs in Documentation Table
1.4	 Added values for 'Maximum operating junction temperature' in Table 8. Added typical values for 'Core operating supply current (master mode)' in Table 9. Added typical values for 'Pad operating supply current (master mode)' in Table 9. Removed unnecessary PLL specifications, #6-9, in Table 10.

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Document Revision History

Table 26. MCF5235EC Revision History (continued)

Rev. No.	Substantive Change(s)
1.5	 Removed Overview, Features, Modes of Operation, and Address Multiplexing sections. This information can be found in the MCF5235 Reference Manual. Removed list of documentation table in Section 8, "Documentation.". An up-to-date list is always available on our web site.
1.6	Table 9: Changed core supply voltage (V _{DD}) from 1.35-1.65 to 1.4-1.6.
1.7	Table 10: Changed max f _{ICO} frequency from "75 MHz" to "150 MHz".
1.8	 Added Section 5.2.1, "Supply Voltage Sequencing and Separation Cautions." Updated 196MAPBGA package dimensions, Figure 3.
2	 Table 2: Changed SD_CKE pin location from 139 to "—" for the 160QFP device. Changed QSPI_CS1 pin location from "—" to 139 for the 160QFP device. Figure 8: Changed pin 139 label from "SD_CKE/QSPI_CS1" to "QSPI_CS1/SD_CKE". Removed second sentence from Section 7.10.1, "MII Receive Signal Timing (ERXD[3:0], ERXDV, ERXER, and ERXCLK)," and Section 7.10.2, "MII Transmit Signal Timing (ETXD[3:0], ETXEN, ETXER, ETXCLK)," regarding no minimum frequency requirement for TXCLK. Removed third and fourth paragraphs from Section 7.10.2, "MII Transmit Signal Timing (ETXD[3:0], ETXEN, ETXER, ETXCLK)," as this feature is not supported on this device.
3	 Section 5.2.1, "Supply Voltage Sequencing and Separation Cautions" changed PLLV_{DD} to V_{DDPLL} to match rest of document. Section 5.2.1, "Supply Voltage Sequencing and Separation Cautions" Changed V_{DDPLL} voltage level from 1.5V to 3.3V throughout section. Section 5.2.1.1, "Power Up Sequence" first bullet, changed "Use 1 μs" to "Use 1 ms". Corrected position of spec D5 in Figure 14. Table 14: Added DACKn and DREQn to footnote. Table 9, added PLL supply voltage row
4	Added part number MCF5235CVF150 in Table 6

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Document Number: MCF5235EC

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